

TLP721(D4)SERIES



Ex.	:	TLP721 (D4-GR-LF4)	D4	:	VDE0884 option
			GR	:	CTR rank
			LF4	:	lead bend

Ex. TLP721 (D4-GR-LF4) \rightarrow TLP721

DESCRIPTION		SYMBOL	RATING	UNIT
Application Classification (DIN VDE0110 Teil 1/01.89, Table 1) for rated mains voltage $\leq 300V_{rms}$ for rated mains voltage $\leq 600V_{rms}$			I-IV I-III	—
Climatic Classification (DIN IEC68 Teil 1/09.80)			40 / 100 / 21	—
Pollution Degree (DIN VDE0110 Teil 1/01.89)			2	—
Maximum Operating Insulation Voltage	TLP721	V_{IORM}	630	V_{pk}
	TLP721F		890	
Input to output Test Voltage, Method A $V_{pr}=1.5 \times V_{IORM}$, Type and Sample Test $t_p=60s$, Partial Discharge $< 5pC$	TLP721	V_{pr}	945	V_{pk}
	TLP721F		1335	
Input to output Test Voltage, Method B $V_{pr}=1.875 \times V_{IORM}$, 100% Production Test $t_p=1s$, Partial Discharge $< 5pC$	TLP721	V_{pr}	1180	V_{pk}
	TLP721F		1670	
Highest Permissible Overvoltage (Transient Overvoltage, $t_{pr}=10s$)		V_{TR}	6000	V_{pk}
Safety Limiting Values (Max. permissible ratings in case of fault, also refer to thermal derating curve) Current (Input current I_F , $P_{Si}=0$) Power (Output or Total Power Dissipation) Temperature		I_{Si} P_{Si} T_{Si}	300 500 150	mA mW °C
Insulation Resistance, $V_{IO}=500V$, $T_a=25^\circ C$ $V_{IO}=500V$, $T_a=T_{Si}$		R_{Si}	$\geq 10^{12}$ $\geq 10^9$	Ω

- This data sheet refers to TLP721 (D4, M), TLP721F (D4, M) that previously has a white-resin mold and have been changed. When designing new products please use black mold-resin devices.

INSULATION RELATED SPECIFICATIONS

		 7.62mm pitch TLP721	 10.16mm pitch TLP721F
Minimum Creepage Distance (*)	Cr	7.0mm	8.0mm
Minimum Clearance (*)	Cl	7.0mm	8.0mm
Minimum Insulation Thickness	ti	0.5mm	
Comperative Tracking Index (DIN IEC112/VDE0303, Part 1)	CTI	175 (VDE0110 Teil 1/01.89 Group III a)	

- (*) in accordance with DIN VDE0110 Teil 1/01.89, Table 2, & 4)
- (*1) If a printed circuit is incorporated, the creepage distance and clearance may be reduced below this value (e. g. at a standard distance between soldering eye centres of 7.5mm). If this is not permissible, the user shall take suitable measures.
 - (*2) This photocoupler is suitable for 'safe electrical isolation' only within the safety limit data.
Maintenance of the safety data shall be ensured by means of protective circuits.

VDE Test sign : Marking on product
for VDE0884

4

Marking on packing
for VDE0884



Marking Example :

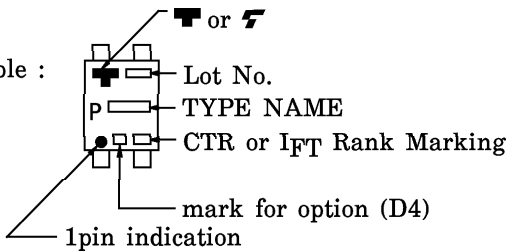


Figure 1 Partial discharge measurement procedure according to VDE0884
Destructive test for qualification and sampling tests.

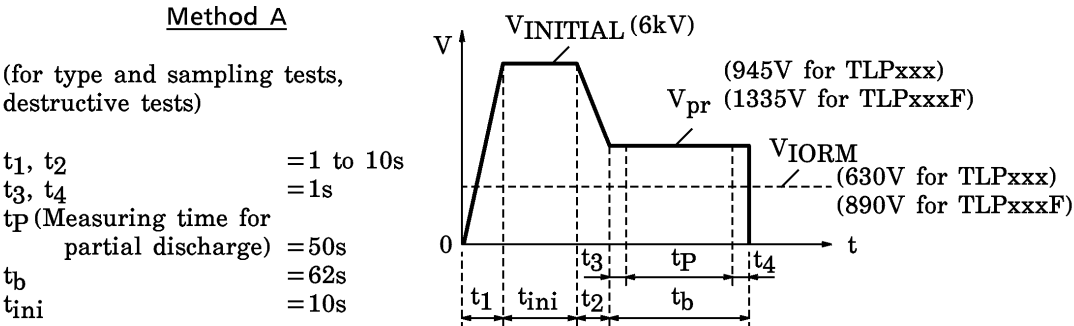


Figure 2 Partial discharge measurement procedure according to VDE0884
Non-destructive test for 100% inspection.

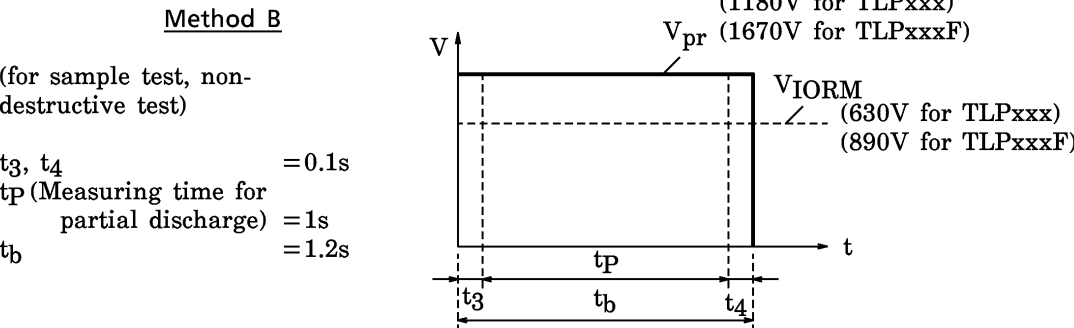
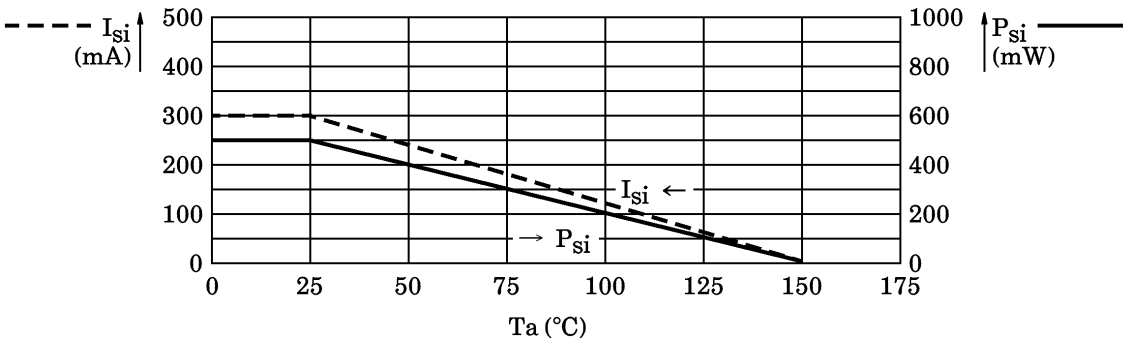


Figure 3 Dependency of maximum safety ratings on ambient temperature



RESTRICTIONS ON PRODUCT USE

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